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 LG, XS, MS, HW

Updated Testing Results for Mimostar-3 New Fabrication

We present updated measurements from our testing of the new fabrication of Mimostar-3. We have discovered and corrected a flaw in our test setup that distorted some of the earlier measurements. This fix has removed the structure in the gain=5 distributions referred to in our earlier report and moved the <sup>55</sup>Fe calibration peak moderately. The updated results are shown below.

MimoSTAR3 and MimoSTAR2 calibrations (04-05/09/2008)

MimoSTAR3 was calibrated at temperature of ~35 deg C (silicon temp).  
 MimoSTAR2 was calibrated at temperature of ~ 32 deg C (silicon temp).

chip	output	Peak [ADC]	Sigma [ADC]	Noise [ADC]	ENC [e-]
Ch1(A2) G=3	1	156	9.8	4.62	48.5
	2	155	9.5	4.52	47.8
Ch1(A2) G=5	1	274	14.9	7.93	47.4
	2	270	15.3	7.51	45.6
Ch2(A4) G=3	1	153	8.8	4.31	46.2
	2	151	9.2	4.01	43.5
Ch2(A4) G=5	1	268	14.3	7.51	45.9
	2	257	9.7	7.12	45.4
Ch6(D3) G=3	1	158	8.8	4.30	44.6
	2	153	7.9	4.13	44.3
Ch6(D3) G=5	1	276	13.5	7.68	45.6
	2	263	14.5	7.30	45.5
MS2 G=3	S0	233	5.5	3.19	22.5
	S1	205	6.6	3.27	26.1
MS2 G=5	S0	401	10.9	4.02	16.4
	S1	352	9.4	4.13	19.2